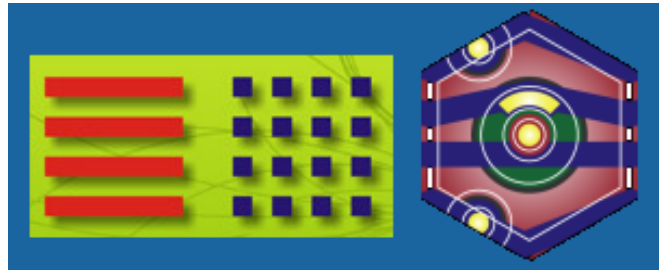


7th Belle II VXD Workshop and 18th International Workshop on DEPFET Detectors and Applications



Contribution ID: 90

Type: **not specified**

Discussion on stress test

Thursday, 22 January 2015 15:00 (15 minutes)

Presenter: HIGUCHI, Takeo (Kavli IPMU)

Session Classification: SVD Parallel Session III